

Patent Application Serial No	10/629,01
	July 28, 2003
	Trung Tri Doan et al
Assignee·	Micron Technology, Inc
Group Art Unit	2812
Examiner	Jennifer M. Kennedy
Attorney's Docket No	
Title	Atomic Layer Deposition Methods

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. Copies of the required cited art references are attached. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed before the mailing of a first office action after the filing of a Request for Continued Examination. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Mark & Matkin Reg. No. 32,268

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(Use several sheets if necessary)				APPLICANT: Trung Tri Doan et al.							
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U.S. PATERIPERIENTS											
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